

File Number 1586

2N6755, 2N6756

Power MOS Field-Effect Transistors

N-Channel Enhancement-Mode Power Field-Effect Transistors

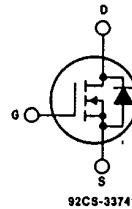
12A and 14A, 60V - 100V

$r_{DS(on)} = 0.18 \Omega$ and 0.25Ω

Features:

- SOA is power-dissipation limited
- Nanosecond switching speeds
- Linear transfer characteristics
- High input impedance
- Majority carrier device

N-CHANNEL ENHANCEMENT MODE



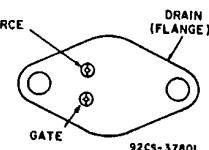
92CS-33741

TERMINAL DIAGRAM

The 2N6755 and 2N6756 are n-channel enhancement-mode silicon-gate power field-effect transistors designed for applications such as switching regulators, switching converters, motor drivers, relay drivers, and drivers for high-power bipolar switching transistors requiring high speed and low gate-drive power. These types can be operated directly from integrated circuits.

These types are supplied in the JEDEC TO-204AA steel package.

TERMINAL DESIGNATION



92CS-37801

JEDEC TO-204AA

Absolute Maximum Ratings

Parameter	2N6755	2N6756	Units
V_{DS} Drain - Source Voltage	60*	100*	V
V_{DGR} Drain - Gate Voltage ($V_{GS} = 20 \text{ k}\Omega$)	60*	100*	V
$I_D @ T_C = 25^\circ\text{C}$ Continuous Drain Current	12*	14*	A
$I_D @ T_C = 100^\circ\text{C}$ Continuous Drain Current	8.0*	9.0*	A
I_{DM} Pulsed Drain Current	25	30	A
V_{GS} Gate - Source Voltage	$\pm 20^*$		V
$P_D @ T_C = 25^\circ\text{C}$ Max. Power Dissipation	75* (See Fig. 11)		W
$P_D @ T_C = 100^\circ\text{C}$ Max. Power Dissipation	30* (See Fig. 11)		W
L_{DM} Linear Derating Factor	0.6* (See Fig. 11)		W/ $^\circ\text{C}$
I_{LM} Inductive Current, Clamped	(See Fig. 1 and 2) $L = 100 \mu\text{H}$ 25	30	A
T_J T_{STG} Operating and Storage Temperature Range	-55* to 150*	--	$^\circ\text{C}$
Lead Temperature	300* (0.063 in. (1.6mm) from case for 10s)		$^\circ\text{C}$

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Electrical Characteristics @ $T_C = 25^\circ\text{C}$ (Unless Otherwise Specified)

Parameter	Type	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS} Drain - Source Breakdown Voltage	2N6755	60	-	-	V	$\text{V}_{\text{GS}} = 0$ $I_D = 10 \text{ mA}$
	2N6756	100	-	-	V	
$\text{V}_{\text{GS(th)}}$ Gate Threshold Voltage	ALL	2.0*	-	4.0*	V	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}, I_D = 1 \text{ mA}$
I_{GSSF} Gate - Body Leakage Forward	ALL	-	-	100*	nA	$\text{V}_{\text{GS}} = 20\text{V}$
I_{GSSR} Gate - Body Leakage Reverse	ALL	-	-	100*	nA	$\text{V}_{\text{GS}} = -20\text{V}$
I_{DSS} Zero Gate Voltage Drain Current	ALL	-	0.1	1.0*	mA	$\text{V}_{\text{DS}} = \text{Max. Rating}, \text{V}_{\text{GS}} = 0$
	ALL	-	0.2	4.0*	mA	$\text{V}_{\text{DS}} = \text{Max. Rating}, \text{V}_{\text{GS}} = 0, T_C = 125^\circ\text{C}$
$\text{V}_{\text{DS(on)}}$ Static Drain-Source On-State Voltage	2N6755	-	-	3.0*	V	$\text{V}_{\text{GS}} = 10\text{V}, I_D = 12\text{A}$
	2N6756	-	-	2.5*	V	$\text{V}_{\text{GS}} = 10\text{V}, I_D = 14\text{A}$
$\text{R}_{\text{DS(on)}}$ Static Drain-Source On-State Resistance	2N6755	-	0.20	0.25*	Ω	$\text{V}_{\text{GS}} = 10\text{V}, I_D = 8\text{A}$
	2N6756	-	0.14	0.18*	Ω	$\text{V}_{\text{GS}} = 10\text{V}, I_D = 9\text{A}$
$\text{R}_{\text{DS(on)}}$ Static Drain-Source On-State Resistance	2N6755	-	-	0.45*	Ω	$\text{V}_{\text{GS}} = 10\text{V}, I_D = 8\text{A}, T_C = 125^\circ\text{C}$
	2N6756	-	-	0.33*	Ω	$\text{V}_{\text{GS}} = 10\text{V}, I_D = 9\text{A}, T_C = 125^\circ\text{C}$
g_f Forward Transconductance	ALL	4.0*	5.5	12.0*	S (U)	$\text{V}_{\text{DS}} = 15\text{V}, I_D = 9\text{A}$
C_{iss} Input Capacitance	ALL	350*	600	800*	pF	
C_{oss} Output Capacitance	ALL	150*	300	500*	pF	$\text{V}_{\text{GS}} = 0, \text{V}_{\text{DS}} = 25\text{V}, f = 10 \text{ MHz}$
C_{rss} Reverse Transfer Capacitance	ALL	50*	100	150*	pF	See Fig. 10
$t_{\text{d(on)}}$ Turn-On Delay Time	ALL	-	-	30*	ns	$\text{V}_{\text{DD}} \geq 36\text{V}, I_D = 9\text{A}, Z_D = 15\Omega$
t_r Rise Time	ALL	-	-	75*	ns	(See Figs. 13 and 14)
$t_{\text{d(off)}}$ Turn-Off Delay Time	ALL	-	-	40*	ns	(MOSFET switching times are essentially independent of operating temperature)
t_f Fall Time	ALL	-	-	45*	ns	

Thermal Resistance

R_{thJC} Junction-to-Case	ALL	-	-	1.67*	$^\circ\text{C}/\text{W}$
R_{thCS} Case-to-Sink	ALL	-	0.1	-	$^\circ\text{C}/\text{W}$
R_{thJA} Junction-to-Ambient	ALL	-	-	30	$^\circ\text{C}/\text{W}$

Body-Drain Diode Ratings and Characteristics

I_S Continuous Source Current (Body Diode)	2N6755	-	-	12*	A	Modified MOSFET symbol showing the integral reverse P-N junction rectifier.
	2N6756	-	-	14*	A	
I_{SM} Pulsed Source Current (Body Diode)	2N6755	-	-	25	A	
	2N6756	-	-	30	A	
V_{SD} Diode Forward Voltage	2N6755	0.85*	-	1.7*	V	$T_C = 25^\circ\text{C}, I_S = 12\text{A}, V_{GS} = 0$
	2N6756	0.90*	-	1.8*	V	$T_C = 25^\circ\text{C}, I_S = 14\text{A}, V_{GS} = 0$
t_{rr} Reverse Recovery Time	ALL	-	300	-	ns	$T_J = 150^\circ\text{C}, I_F = I_{SM}, dI/dt = 100 \text{ A}/\mu\text{s}$
Q_{RR} Reverse Recovered Charge	ALL	-	4.0	-	μC	$T_J = 150^\circ\text{C}, I_F = I_{SM}, dI/dt = 100 \text{ A}/\mu\text{s}$

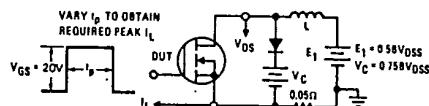
*JEDEC registered values ① Pulse Test: Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$ 

Fig. 1 - Clamped Inductive Test Circuit



Fig. 2 - Clamped Inductive Waveforms

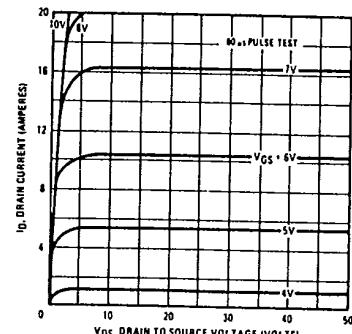


Fig. 3 - Typical Output Characteristics

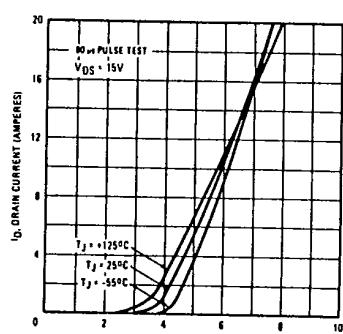


Fig. 4 - Typical Transfer Characteristics

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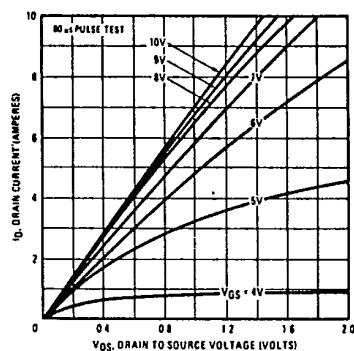


Fig. 5 – Typical Saturation Characteristics
(2N6755)

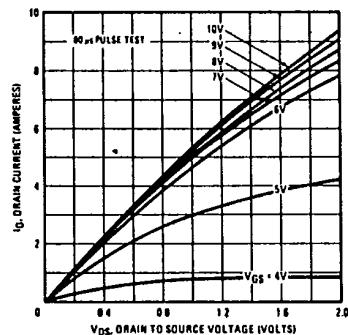


Fig. 6 – Typical Saturation Characteristics
(2N6756)

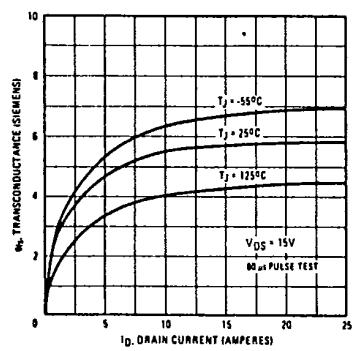


Fig. 7 – Typical Transconductance Vs. Drain Current

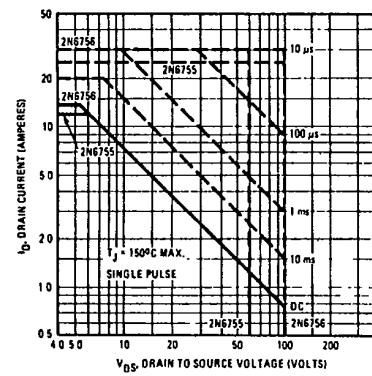


Fig. 8 – Maximum Safe Operating Area

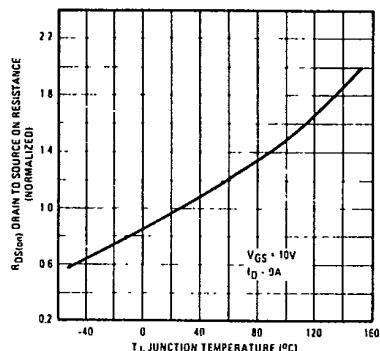


Fig. 9 – Normalized Typical On-Resistance Vs. Temperature

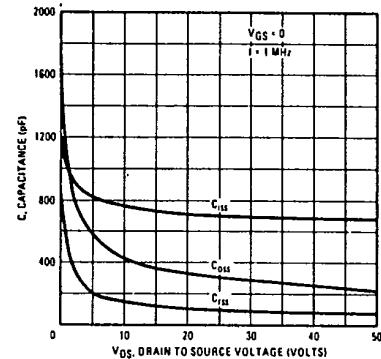


Fig. 10 – Typical Capacitance Vs. Drain-to-Source Voltage

Standard Power MOSFETs

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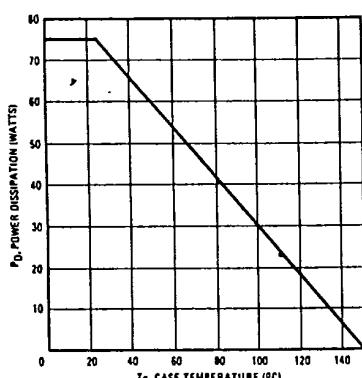


Fig. 11 - Power Vs. Temperature Derating Curve

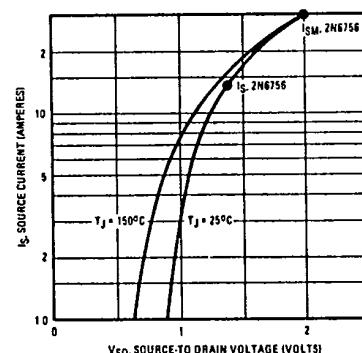


Fig. 12 - Typical Body-Drain Diode Forward Voltage

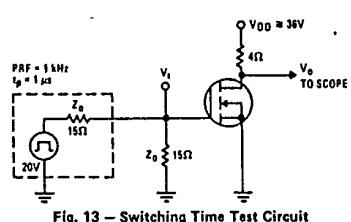


Fig. 13 - Switching Time Test Circuit

